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April 1, 2003

E8000 SH7055 Emulator  
Diagnostic Program Manual

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Throughout this document, the term "emulator product" shall be defined as the following products produced only by Hitachi, Ltd. excluding all subsidiary products.

- Emulator station
- Device control board
- EV-chip board

The user system or a host computer is not included in this definition.

### **Purpose of the Emulator Product:**

This emulator product is a software and hardware development tool for systems employing the Hitachi microcomputer HD64F7055 (hereinafter referred to as SH7055). By exchanging the device control board and EV-chip board, this emulator product can also be used for systems using Hitachi microcomputers supported by other E8000-series emulators. This emulator product must only be used for the above purpose.

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This emulator product should only be used by those who have carefully read and thoroughly understood the information and restrictions contained in the user's manual. Do not attempt to use the emulator product until you fully understand its mechanism.

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**Figures:**

Some figures in this diagnostic program manual may show items different from your actual system.

**Limited Anticipation of Danger:**

Hitachi cannot anticipate every possible circumstance that might involve a potential hazard. The warnings in this diagnostic program manual and on the emulator product are therefore not all inclusive. Therefore, you must use the emulator product safely at your own risk.

# SAFETY PAGE

## READ FIRST

- **READ** this user's manual before using this emulator product.
- **KEEP the user's manual handy for future reference.**

Do not attempt to use the emulator product until you fully understand its mechanism.

## DEFINITION OF SIGNAL WORDS

**DANGER** indicates an **imminently** hazardous situation which, **if not avoided**, will result in **DEATH** or **SERIOUS INJURY** to you or other people.

**WARNING** indicates a **potentially** hazardous situation which, **if not avoided**, could result in **DEATH** or **SERIOUS INJURY** to you or other people.

**CAUTION** indicates a hazardous situation which, **if not avoided**, may result in **minor or moderate injury** to you or other people, or may result in **damage to the machine, or loss of the user program**. It may also be used to alert against unsafe usage.

**NOTE** emphasizes essential information.



## WARNING

Observe the precautions listed below. Failure to do so will result in a FIRE HAZARD and will damage the user system and the emulator product or will result in PERSONAL INJURY. The USER PROGRAM will be LOST.

1. Carefully handle the emulator product to prevent receiving an electric shock because the emulator product has a DC power supply. Do not repair or remodel the emulator product by yourself for electric shock prevention and quality assurance.
2. Always switch **OFF** the emulator product and the user system before connecting or disconnecting any CABLES or PARTS.
3. Always before connecting, make sure the connection direction is correct.
4. Supply power according to the power specifications and do not apply an incorrect power voltage. Use only the provided AC power cable. Use only the specified type of fuse.



## Warnings on Emulator Usage

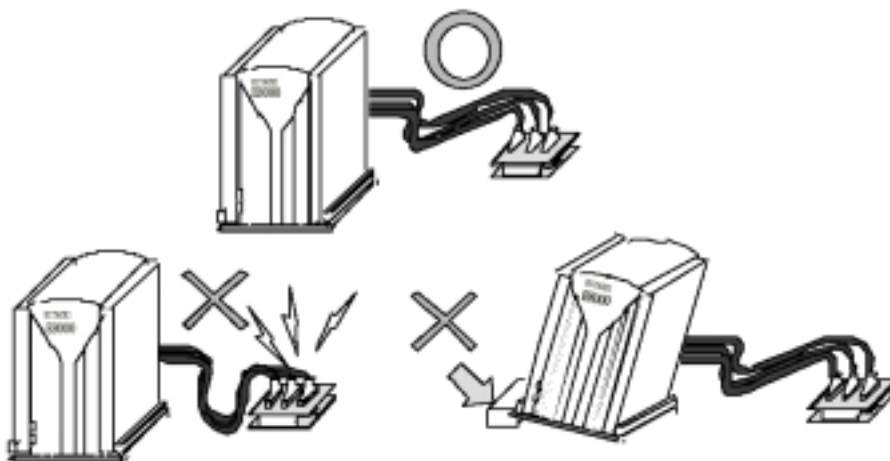
Warnings described below apply as long as you use this emulator. Be sure to read and understand the warnings below before using this emulator. Note that these are the main warnings, not the complete list.



Always switch OFF the emulator and user system before connecting or disconnecting any CABLES or PARTS. Failure to do so will result in a FIRE HAZARD and will damage the user system and the emulator product or will result in PERSONAL INJURY. The USER PROGRAM will be LOST.



Place the emulator station and EV-chip board so that the trace cables are not bent or twisted. A bent or twisted cable will impose stress on the user interface leading to connection or contact failure. Make sure that the emulator station is placed in a secure position so that it does not move during use nor impose stress on the user interface.



# Preface

Thank you for purchasing the E8000 emulator for Hitachi's original microcomputer SH7055.

The diagnostic program automatically checks whether the E8000 emulator is operating correctly.

**Read this manual and understand it before using the diagnostic program.**

# Contents

Section 1	Overview .....	1
1.1	Purpose.....	1
Section 2	Configuration .....	2
2.1	Test System Configuration .....	2
Section 3	Diagnostic Program Function .....	4
3.1	General Description .....	4
3.2	Test Items.....	6
3.3	Operation Flowchart.....	8
3.4	Data Output to the Printer.....	9
Section 4	Procedures .....	11
4.1	Installation Procedure.....	12
4.2	Operation Procedure .....	14
Section 5	Error Handling .....	23
Section 6	Testing Circuits and Connectors .....	24
6.1	Testing Circuit for P1284 I/F TEST (TEST 07).....	24
6.2	Testing Circuit for SERIAL I/F TEST (TEST 08) .....	24
6.3	Serial Interface Connector.....	25
6.4	Bidirectional Parallel Interface Connector .....	26

# Section 1 Overview

## 1.1 Purpose

This diagnostic program is used to automatically troubleshoot and maintain an SH7055 E8000 emulator hardware system.

The diagnostic program is on a 3.5-inch floppy disk (HS7055EDD81SF). When an error occurs, execute the diagnostic program according to section 4, Diagnostic Program Operation Procedure.

- Notes:**
- 1. This diagnostic program is not capable of finding all failures possible to occur in the E8000 emulator.**
  - 2. If execution results of the diagnostic program indicate a failure in the E8000 emulator, inform a Hitachi sales agency of the test results in detail.**
  - 3. Hitachi makes no warranties for an E8000 emulator that has been taken apart, repaired, or remodeled by the user based on the test results of the diagnostic program.**
  - 4. In addition to this diagnostic program, run the emulator internal system test described in section 5, Troubleshooting, in the E8000 SH7055 Emulator User's Manual (HS7055EDD81HE).**

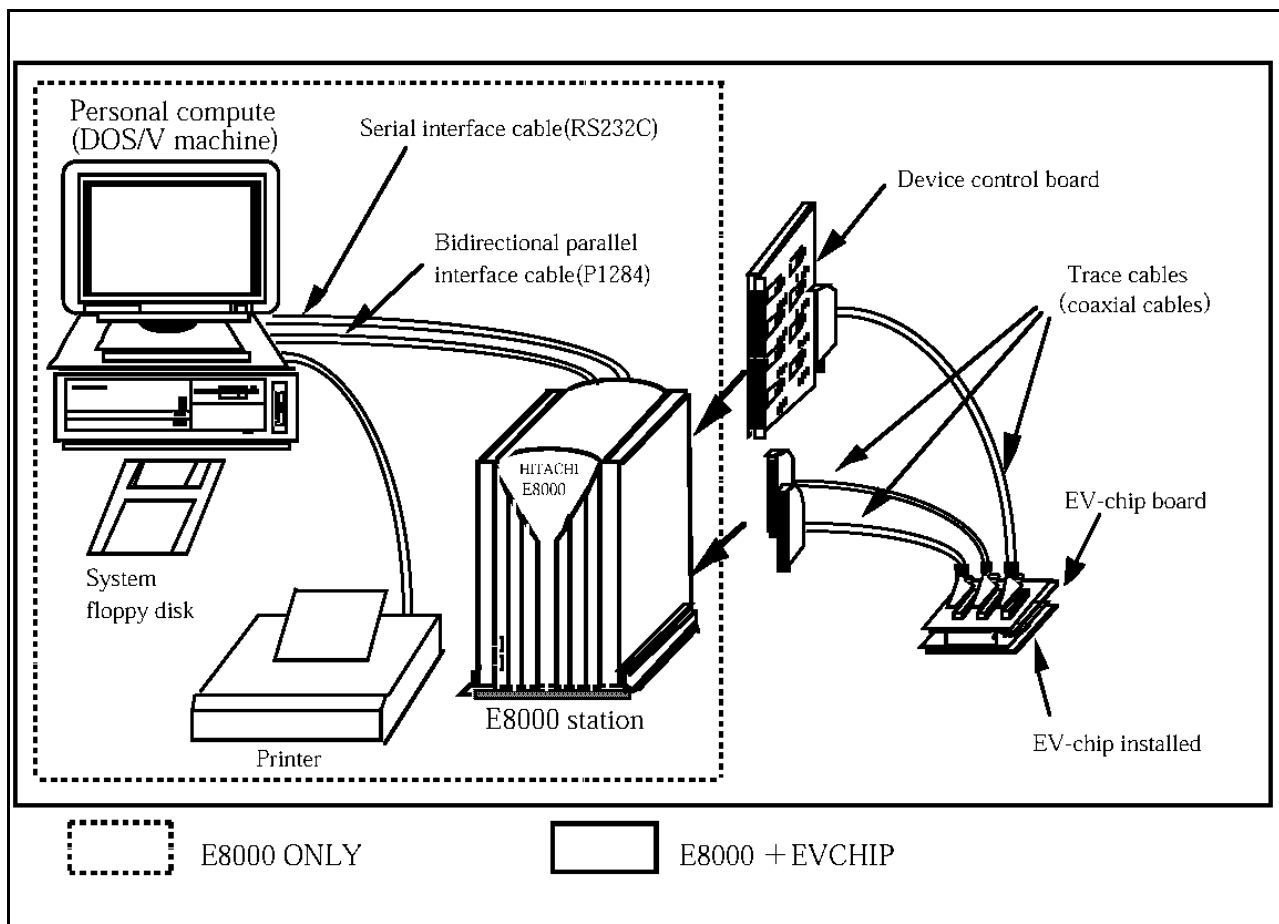
## Section 2 Configuration

### 2.1 Test System Configuration

Components required for diagnostic program execution are shown in table 2.1, and the test system configuration is shown in figure 2.1.

**Table 2.1 Test System Components**

<b>Components</b>		<b>Remarks</b>
E8000 emulator (HS8000EST02H)	Control board (HS8000PWB81H)	Always necessary
	Device control board (HS7055EDD81H)	Always necessary
	Trace board (HS8000PWB82H)	Always necessary
	PC I/F board (HS8000PWB85H)	Always necessary
LAN board (HS7000ELN01H or HS7000ELN02H)		Depends on user system configuration
EV-chip board (HS7055EBK81H)		Always necessary
Serial interface cable (RS232C)		Always necessary
Bidirectional parallel interface cable (P1284)		Optional
Personal computer (DOS/V machine)		Always necessary
System floppy disk (HS7055EDD81SF) (Host interface software (IPW) included)		Always necessary
Printer		Optional



**Figure 2.1 Test System Configuration**

## Section 3 Diagnostic Program Function

### 3.1 General Description

The diagnostic program has three test-system configurations: E8000 ONLY test and E8000 + EVCHIP test (which are independent E8000 emulator system tests) and E8000 + EVCHIP + FIXED USER test. Note that the E8000 + EVCHIP + FIXED USER test cannot be executed, for it is the E8000 emulator system test at shipment and needs an additional system for testing.

#### **CAUTION**

Before executing an independent E8000 emulator system test, remove the EV-CHIP BOARD from the USER SYSTEM and USER SYSTEM INTERFACE CABLE. Correct test results cannot be obtained when the E8000 emulator is still connected to the user system.

#### **Independent E8000 Emulator System Test (E8000 ONLY):**

The system configuration shown in figure 2.1 is used for testing the independent E8000 emulator system. The test results are displayed on the personal computer display. After start-up, the system enters an endless test loop without operator intervention until an error is detected. When an error occurs and ERROR CONTINUE is not specified, the test is terminated. If ERROR CONTINUE is specified, the test resumes execution after an error content display. When initiating the diagnostic program, select whether to execute the following tests:

- Operation tests
- Serial interface test
- Bidirectional parallel interface test
- LAN board (optional) test

## **Test of E8000 Emulator, SH7055 Device Control Board, and SH7055 EV-Chip Board (E8000 + EVCHIP):**

The system configuration shown in figure 2.1 is used for testing the E8000 emulator, and the SH7055 device control board and SH7055 EV-chip board for the E8000 emulator. The test results are displayed on the personal computer display. After start-up, the system enters an endless test loop without operator intervention until an error is detected. When an error occurs and ERROR CONTINUE is not specified, the test is terminated. If ERROR CONTINUE is specified, the test resumes execution after an error content display. When initiating the diagnostic program, select whether to execute the following tests:

- Operation tests
- Serial interface test
- Bidirectional parallel interface test
- LAN board (optional) test

**Notes:**

- 1. To stop diagnostic program execution, press the (CTRL) + C keys and interrupt the test.**
- 2. The Bidirectional parallel interface and serial interface tests require additional circuits. Prepare the necessary circuits according to the diagrams in section 6, Testing Circuits and Connectors, before selecting the Bidirectional parallel interface and serial interface tests.**
- 3. The LAN board must be installed in the E8000 station and connected to LAN when performing the LAN board (optional) test.**



## 3.2 Test Items

Test items are listed in table 3.1. The test items to be executed depend on the test system configuration.

**Table 3.1 Diagnostic Program Test Items**

No.	Test Item	Description	Executed or Not	
			E8000 ONLY	E8000 + EVCHIP
TEST01	FLASH MEMORY READ TEST	Control board flash memory test	O	O
TEST02	CONT WORK RAM TEST	Control board work RAM test	O	O
TEST03	SHARED RAM TEST	Trace board RAM test	O	O
TEST04	FIRM RAM TEST	Firmware RAM test	O	O
TEST05	OPTION I/F TEST	Optional host computer I/F DPRAM test	O	O
TEST06	LAN I/F TEST	LAN board interface test	Δ	Δ
TEST07	P1284 I/F TEST	Bidirectional parallel interface test	Δ	Δ
TEST08	SERIAL I/F TEST	Serial interface test	Δ	Δ
TEST09	JTAG TEST	JTAG controller test	O	O
TEST10	CONT REG. TEST	Control board register test	O	O
TEST11	IDR READ	E8000 hardware configuration check	O	O
TEST12	DIP SWITCH TEST	Control board DIP switch test	Δ	Δ
TEST13	TRACE REG. TEST	Trace board register test	O	O
TEST14	TRACE RAM TEST	Trace board RAM test	O	O
TEST15	PARALLEL RAM TEST	Parallel RAM test	O	O
TEST16	EBOX TEST	DCONT firmware and ID check	X	O
TEST17	ERAM WINDOW TEST	ERAM read/write test	X	O
TEST18	ERAM STEP TEST	ERAM step test	X	O
TEST19	ERAM HARD BREAK TEST1	ERAM hardware break test	X	O
TEST20	ERAM HARD BREAK TEST2	ERAM hardware break test	X	O
TEST21	ERAM SOFT BREAK TEST	ERAM software break test	X	O
TEST22	COMPULSORY BREAK TEST	CBR register break test	X	O
TEST23	ERAM TRACE TEST	ERAM trace mode test	X	O
TEST24	ERAM TIME MEASURE TEST	Time measurement function check	X	O
TEST25	ERAM PARALLEL MONITOR TEST	ERAM parallel monitor test	X	O
TEST26	INROM WRITE PROTECT TEST	INROM write protect test	X	O
TEST27	COVERAGE TEST	COVERAGE RAM read/write test	X	O

**Notes:** O: Executed without operator intervention

Δ: Executed when specified

X: Not executed

**Note: If an error occurs and ERROR CONTINUE is not specified, displays an error message, stops test execution, and displays the following message:**

**Retry (Y/N) ?**

**If Y is entered, retests the test item wherein the error occurred.**

**If N is entered, displays the following message:**

**Continue (Y/N) ?**

**If Y is entered, quits testing the test item wherein the error occurred and goes on to the next test item.**

**If N is entered, displays the following message:**

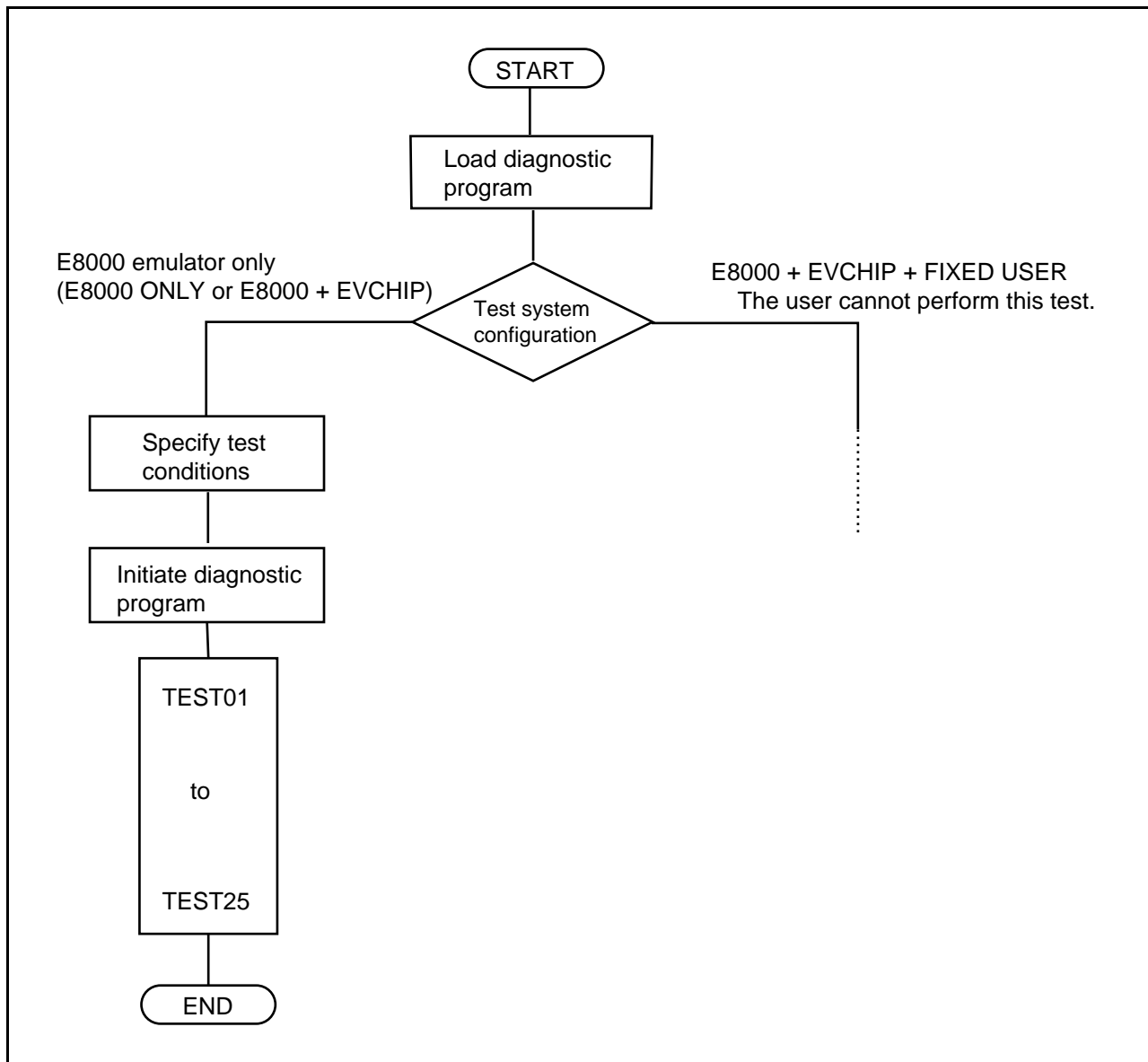
**Abort (Y/N) ?**

**If Y is entered, resets the system software.**

**If N is entered, returns to the first message (Retry (Y/N) ?) and repeats the above procedure until Y is entered.**

### 3.3 Operation Flowchart

Figure 3.1 shows the diagnostic program operation flowchart.



**Figure 3.1 Diagnostic Program Operation Flowchart**

**Note:** TEST06 is executed when the optional LAN board test is specified.  
TEST07 is executed when the Bidirectional parallel interface test is specified.  
TEST08 is executed when the serial interface test is specified.  
TEST12 is executed when the operation tests are specified.  
TEST16 to TEST25 are not executed when the E8000 ONLY test is selected.

### 3.4 Data Output to the Printer

The following describes the process for sending diagnostic program execution results to the printer using the E8000 emulator.

#### Diagnostic Program Output to Printer

START E8000

S: START E8000

F: FLASH MEMORY TOOL

L: SET LAN PARAMETER

T: START DIAGNOSTIC TEST

(S/F/L/T) ? >a:TM.LOG (RET) (a)

(S/F/L/T) ? t (RET) (b)

(Diagnostic program execution)

(CTRL) + C (c)

>q (RET) (d)

E8000 MONITOR (HS8000EST02SR) Vn.m

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TESTING

RAM 0123

START E8000

S: START E8000

F: FLASH MEMORY TOOL

L: SET LAN PARAMETER

T: START DIAGNOSTIC TEST

(S/F/L/T) ? >- (RET) (e)

**Notes: 1. Underlined sections should be entered by the user.**

**2. (RET): RETURN key**

Description:

- (a) Enter the following command after the emulator monitor command prompt.

>a:TM.LOG (RET)

In the above example, a indicates drive a and TM.LOG indicates the file name.

**Note: When selecting drive a, insert the floppy disk in the floppy disk drive before executing this command.**

- (b) Execute the diagnostic program.

- (c) Press the (CTRL) + C keys after executing the diagnostic program.

- (d) Enter the following command to return to the monitor command input wait state.

>q (RET)

- (e) Enter the following command in the monitor command input wait state to terminate data output to the file.

>- (RET)

- (f) Printing.

Open the file (TM.LOG) to which the diagnostic program execution results were output and output the data to a printer from the personal computer used. The file can be opened from the existing editor of the personal computer used.

## Section 4 Procedures

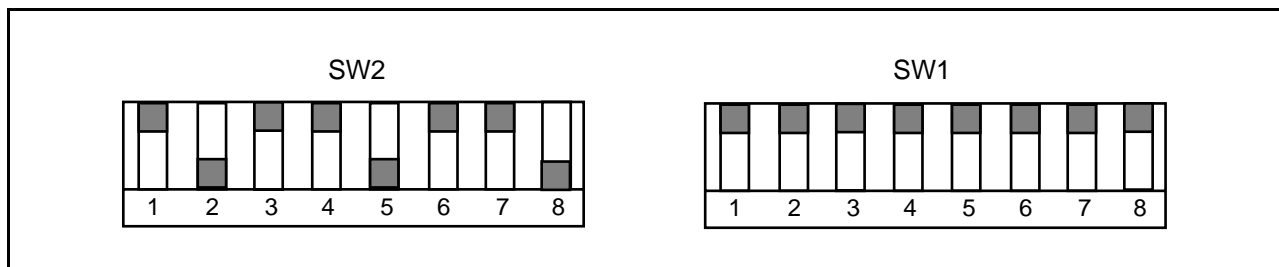
This section describes the diagnostic program operation procedure.



### WARNING

Always switch **OFF** all devices before connecting or disconnecting the E8000 EMULATOR and OTHER DEVICES. Failure to do so will result in a FIRE HAZARD and will damage the E8000 emulator and other devices, or will result in PERSONAL INJURY.

- Notes:**
1. To execute the diagnostic program, DIAG.SYS must be installed in flash memory, according to the instructions in the E8000 SH7055 Emulator User's Manual (HS7055EDD81HE).
  2. Before executing the diagnostic program, make sure the DIP switches have the same settings as at shipment (refer to figure 4.1).
  3. When using the PCIF interface, execute the diagnostic program from HDI.



**Figure 4.1 DIP Switch Setting at Shipment**

## 4.1 Installation Procedure

To execute the diagnostic program, file DIAG.SYS must be installed in the E8000 emulator flash memory.

If the E8000 emulator is connected to the host computer via the bidirectional parallel interface, the diagnostic program can be loaded with the following procedure. Note that the system disk is assumed to be inserted in drive A of the host computer. It takes approximately one minute.

### Operations

### Display Message

- |   |  |
|---|--|
| 1. Initiate the E8000 system floppy disk IPW.   |  |
| 2. Power on the E8000 emulator.   |  |
| 3. Emulator monitor command prompt  | START E8000<br>S:START E8000<br>F:FLASH MEMORY TOOL<br>L:SET LAN PARAMETER<br>T:START DIAGNOSTIC TEST<br>(S/F/L/T) ? _ |
| 4. Enter F (RET) to initiate the flash memory management tool. The emulator displays prompt FM> and waits for a flash memory management tool command. | (S/F/L/T) ? <u>F (RET)</u><br>FM>  |
| 5. Enter SL (RET) to load the system program.   | FM> <u>SL (RET)</u>  |
| 6. Enter 1 (RET) to select PC as the host computer type, and 2 (RET) to select parallel interface as the interface method.                            | SELECT LOAD No. (1:PC or 2:WS) ? <u>1 (RET)</u><br>SELECT INTERFACE (1:RS-232C or 2:PARALLEL) ? <u>2 (RET)</u>         |
| 7. Enter N (RET) to not load system program E8000.SYS.  | LOAD E8000 SYSTEM FILE OK (Y/N) ? <u>N (RET)</u>   |
| 8. Enter N (RET) to not load configuration file SHCNF761.SYS.   | LOAD CONFIGURATION FILE OK (Y/N) ? <u>N (RET)</u>  |
| 9. Enter N (RET) to not load firmware file SHDCT761.SYS.  | LOAD FIRMWARE FILE OK (Y/N) ? <u>N (RET)</u>   |
| 10. Enter N (RET) to not load the ITRON debugger.   | LOAD ITRON DEBUGGER FILE OK (Y/N) ? <u>N (RET)</u>   |

## Operations

## Display Message

11. Enter Y (RET) to allow the diagnostic program file DIAG.SYS to be loaded. Then enter the parallel transfer command to load DIAG.SYS in the current directory on the PC to the emulator flash memory.
- LOAD DIAGNOSTIC FILE OK (Y/N) ? Y (RET)  
INPUT COMMAND : #B:A:/DIAG.SYS (RET)  
:COMPLETED
12. Enter DIR (RET) to check whether the necessary files have been loaded.
- FM> DIR (RET)
- | <FILE ID> | <STATUS> |
|-----------|----------|
| SYS       | OK       |
| CONF      | OK       |
| LAN       | NO       |
| FIRM      | OK       |
| TRON      | NO       |
| DIAG      | OK       |
| INI       | OK       |
| MON       | OK       |
13. Enter Q (RET) to terminate the flash memory management tool.
- FM> Q (RET)
- START E8000  
S:START E8000  
F:FLASH MEMORY TOOL  
L:SET LAN PARAMETER  
T:START DIAGNOSTIC TEST  
(S/F/L/T) ? \_
14. Installation is completed.



## 4.2 Operation Procedure

1. Correctly connect the following components.

- E8000 emulator and personal computer (RS232C interface)
- E8000 emulator and EV-chip board (when the E8000 + EVCHIP test is selected)

For other components, check connection according to the user system configuration.

### **Remove the EV-chip board from the user system.**

2. Turn on the following power supplies.

- Personal computer
- E8000 emulator

For other components, supply an appropriate voltage according to the user system configuration.

3. Start up the host interface software (IPW) on the personal computer.

After the host interface software (IPW) is initiated, the E8000 emulator executes a self-diagnostic test which checks the internal RAM and the registers while displaying the starting message shown on the following page. For details, refer to section 5, Troubleshooting, in the E8000 SH7055 Emulator User's Manual (HS7055EDD81HE).

## E8000 Emulator Starting Message

EMULATOR INTERFACE (HS8000EIW01SF) Vn.m  
Copyright (C) Hitachi, Ltd. 1996  
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E8000 MONITOR (HS8000EST02SR) Vn.m  
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TESTING

RAM 0123

START E8000

S:START E8000

F:FLASH MEMORY TOOL

L:SET LAN PARAMETER

T:START DIAGNOSTIC TEST

(S/F/L/T) ?

**Notes: 1. Underlined sections should be entered by the user. Both uppercase and lowercase letters are acceptable.**

**2. (RET): RETURN key**

4. Load the diagnostic program according to the following procedure.

### Loading Diagnostic Program

START E8000

S:START E8000

F:FLASH MEMORY TOOL

L:SET LAN PARAMETER

T:START DIAGNOSTIC TEST

(S/F/L/T) ? T (RET)

E8000 EMULATOR TEST & MAINTENANCE PROGRAM (DIAG.SYS)

Version No.=x.xx mm/dd/yyyy

Copyright (C) Hitachi, Ltd. 1998

5. Specify the test condition.

When the diagnostic program is loaded and the following message is displayed on the personal computer, select the desired test conditions.

## Test Condition Specifications

Please, key in TEST PARAMETER

OPERATION TEST EXECUTE (Y/N) ? N (RET) (a)

ERROR CONTINUE (Y/N) ? N (RET) (b)

TEST MODE SELECT

1. E8000 ONLY

2. E8000 + EVCHIP

3. E8000 + EVCHIP + FIXED USER

TEST MODE (1/2/3) ? 2 (RET) (c)

DEVICE TYPE SH7055

RS232C LOOP CONNECTOR EXIST (Y/N) ? N (RET) (d)

PARALLEL LOOP CONNECTOR EXIST (Y/N) ? N (RET) (e)

OPTION LAN BOARD EXIST (Y/N) ? N (RET) (f)

START (Y/N) ? Y (RET) (g)

### Description:

- (a) Only for tests requiring operator intervention. Enter Y to execute the operation tests. Otherwise, enter N.
  - (b) Y: Test continues when an error occurs.  
N: Test stops when an error occurs.
  - (c) 1: Independent E8000 emulator system test  
2: E8000 emulator, device control board, and EV-chip board test  
3: E8000 emulator system test at shipment — cannot be used.
  - (d) Enter Y to execute the serial interface test. Otherwise, enter N.
  - (e) Enter Y to execute the bidirectional parallel interface test. Otherwise, enter N.
  - (f) Enter Y to execute the optional LAN board test. Otherwise, enter N.
  - (g) The test starts by entering Y. If N is entered, the diagnostic program main title will be displayed again.
6. Execute the diagnostic program using the procedure shown in figure 3.1.  
Execute each test item following the diagnostic program specifications. OK is displayed if a test is executed with no errors. An example of the E8000 + EVCHIP test is shown on pages 18 to 20.

7. For executing the bidirectional parallel interface test (TEST07)

To execute the bidirectional parallel interface test, install the P1284 loop connector described in section 6.1, Testing Circuit for P1284 I/F Test (TEST07), onto the bidirectional parallel interface connector on the E8000 emulator before executing the diagnostic program. Perform the following operations while executing the bidirectional parallel interface test.

**Operation Procedures for TEST07 (P1284 I/F TEST):**

- (1) Before executing the diagnostic program, install the P1284 loop connector, as shown in figure 4.2.
- (2) Enter Y to the following message at diagnostic program initiation:

PARALLEL LOOP CONNECTOR EXIST (Y/N) ? Y (RET)

- (3) When the diagnostic program is executed, the bidirectional parallel interface test will be executed without operator interventions. If no error occurs, the following messages are displayed:

```
TEST07 P1284 I/F TEST          (COUNT = 001)
      FIFO R/W TEST              OK
      PARALLEL INTERRUPT TEST    OK
```

8. For executing the serial interface test (TEST08)

To execute the serial interface test, install the RS232C loop connector described in section 6.2, Testing Circuit for SERIAL I/F Test (TEST08), onto the serial interface connector on the E8000 emulator before executing the diagnostic program. Perform the following operations while executing the serial interface test.

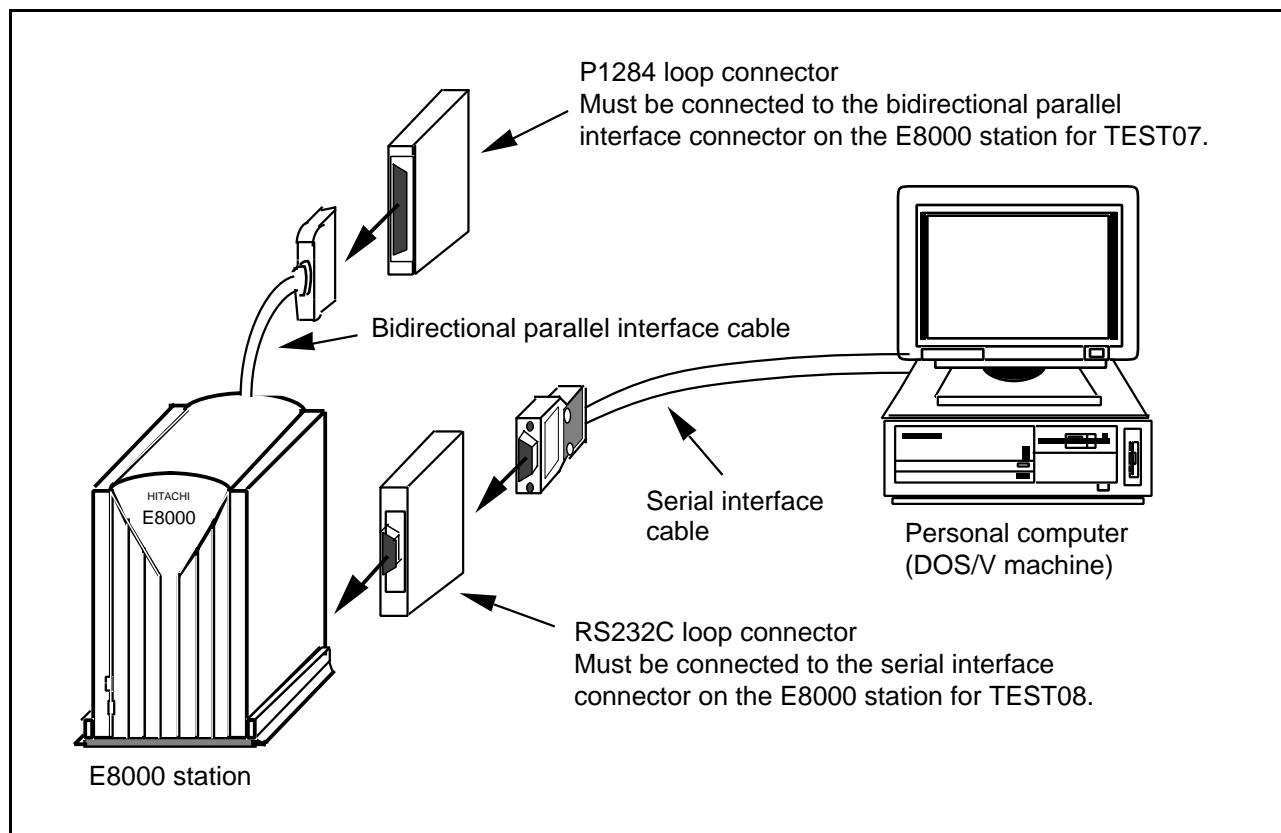
**Operation Procedures for TEST08 (SERIAL I/F TEST):**

- (1) Before executing the diagnostic program, install the RS232C loop connector, as shown in figure 4.2.
- (2) Enter Y to the following message at diagnostic program initiation:

RS232C LOOP CONNECTOR EXIST (Y/N) ? Y (RET)

- (3) When the diagnostic program is executed, the serial interface test will be executed without operator interventions. If no error occurs, the following message is displayed:

```
TEST08 SERIAL I/F TEST      (COUNT = 001)    OK
```



**Figure 4.2 Loop Connector Installation**

9. For executing the operation tests (TEST12)

To execute the operation tests, operator interventions are required during diagnostic program execution. Perform the following operations while executing the operation tests.

**Operation Procedures for TEST12 (DIP SWITCH TEST):**

- (1) Enter Y to the following message at diagnostic program initiation:

```
OPERATION TEST EXECUTE (Y/N)? Y (RET)
```

- (2) When the diagnostic program is executed, the E8000 emulator will halt at the following message and wait for command input:

```
TEST12 DIP SWITCH TEST          (COUNT = 001)
DIPSW 1 - 2 = 0092
DIPSW 1 - 2 = H'5555   SET OK (Y/N)
```

- (3) After setting the DIP switches as shown in figure 4.3 (1), enter Y.

- (4) If no error occurs, the following message is displayed:

```
DIPSWITCH 1 - 2 = H'5555   5555   OK
```

- (5) The E8000 emulator will halt again at the following message:

```
DIPSW 1 - 2 = H'AAAA   SET OK (Y/N)
```

- (6) After setting the DIP switches as shown in figure 4.3 (2), enter Y.

(7) If no error occurs, the following message is displayed:

DIPSWITCH 1 - 2 = H'AAAA AAAA OK

(8) The E8000 emulator will halt again at the following message:

DIPSW 1 - 2 = 0092 SET OK (Y/N)

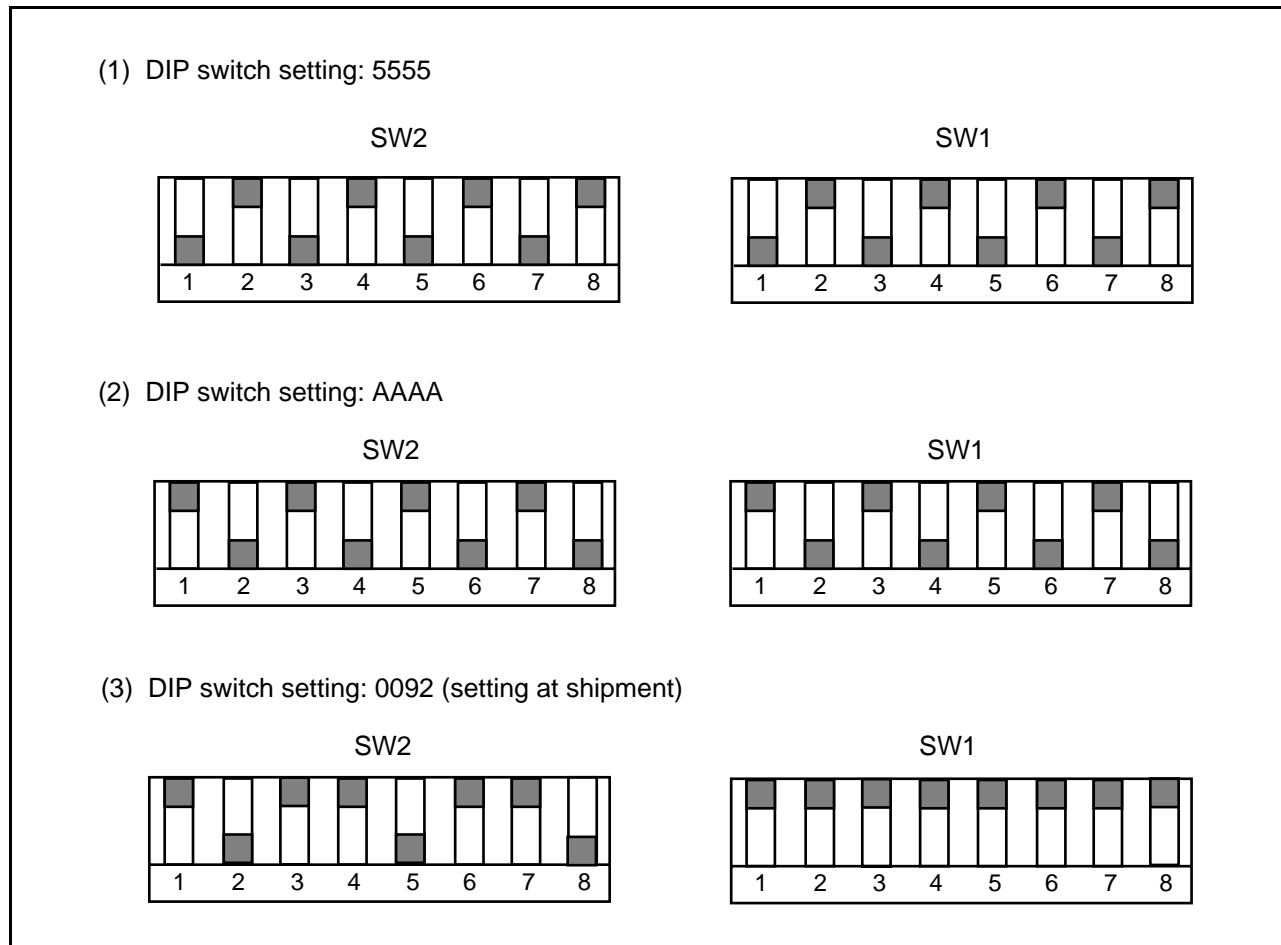
(9) After setting the DIP switches as shown in figure 4.3 (3), enter Y.

(10) If no error occurs, the following message is displayed:

DIPSWITCH 1 - 2 = 0092 0092 OK

TEST END

**Note: (RET): RETURN key**



**Figure 4.3 DIP Switch Settings**

## Diagnostic Program Output Example (E8000 + EVCHIP Test)

E8000 EMULATOR TEST & MAINTENANCE PROGRAM (DIAG.SYS)

Version No. = x.xx      mm/dd/yyyy      (x.xx indicates the version number.)

Copyright (C) Hitachi, Ltd. 1997

Please, key in TEST PARAMETER

OPERATION TEST EXECUTE (Y/N) ? N

ERROR CONTINUE (Y/N) ? N

TEST MODE SELECT

1. E8000 ONLY
2. E8000 + EVCHIP
3. E8000 + EVCHIP + FIXED USER

TEST MODE (1/2/3) ? 2

DEVICE TYPE SH7055

RS232C LOOP CONNECTOR EXIST (Y/N) ? N

PARALLEL LOOP CONNECTOR EXIST (Y/N) ? N

OPTION LAN BOARD EXIST (Y/N) ? N

START (Y/N) ? Y

TEST01 FLASH MEMORY READ TEST      (COUNT = 001)

- |                           |    |
|---------------------------|----|
| (1) MONITOR SUM CHECK     | OK |
| (2) SYSTEM SUM CHECK      | OK |
| (3) EVCHIP FIRM SUM CHECK | OK |
| (4) CONFIG SUM CHECK      | OK |
| (5) T/M SUM CHECK         | OK |
| (6) LAN SUM CHECK         |    |
| NO LAN FILE               |    |
| (7) ITRON SUM CHECK       |    |
| NO TRON FILE              |    |

TEST02 CONT WORK RAM TEST      (COUNT = 001)

- |                   |    |
|-------------------|----|
| (1) PAUSE TEST    | OK |
| (2) MARCHING TEST | OK |

TEST03 SHARED RAM TEST      (COUNT = 001)

- |                   |    |
|-------------------|----|
| (1) PAUSE TEST    | OK |
| (2) MARCHING TEST | OK |

TEST04 FIRM RAM TEST      (COUNT = 001)

- |                   |    |
|-------------------|----|
| (1) PAUSE TEST    | OK |
| (2) MARCHING TEST | OK |

TEST05 OPTION I/F TEST      (COUNT = 001)

- |                         |    |
|-------------------------|----|
| (1) DPRAM PAUSE TEST    | OK |
| (2) DPRAM MARCHING TEST | OK |

## Diagnostic Program Output Example (E8000 + EVCHIP Test) (cont)

```
TEST09 JTAG TEST                (COUNT = 001)      OK
TEST10 CONT REG. TEST           (COUNT = 001)      OK
TEST11 IDR READ TEST            (COUNT = 001)
    ID CODE = FCFE
    PC I/F BOARD                : DISCONNECT
    TRC BOARD                    : CONNECT
    DCONT BOARD                  : CONNECT
    EVCH BOARD                   : CONNECT
    LAN BOARD                    : DISCONNECT
TEST13 TRACE REG. TEST          (COUNT = 001)      OK
TEST14 TRACE RAM TEST           (COUNT = 001)
    (1) PAUSE TEST              OK
    (2) MARCHING TEST           OK
TEST15 PARALLEL RAM TEST        (COUNT = 001)
    (1) PAUSE TEST              OK
    (2) MARCHING TEST           OK
TEST16 EBOX TEST                (COUNT = 001)
    (1) EBOX ID CODE            OK
    (2) EBOX ID CHECK           OK
    (3) SHARED RAM TEST         OK
    (4) WORK RAM TEST           OK
    (5) ULSR TEST               OK
    (6) MAPR R/W TEST           OK
TEST17 ERAM WINDOW TEST         (COUNT = 001)
    (1) ERAM WINDOW TEST        OK
    (2) ERAM WP TEST            OK
    (3) ERAM GDD TEST           OK
    (4) INROM READ/WRITE TEST   OK
TEST18 ERAM STEP TEST           (COUNT = 001)      OK
TEST19 ERAM HARD BREAK TEST1    (COUNT = 001)
    (1) UBC HARDBREAK TEST      OK
    (2) CHA0-7 HARDBREAK TEST   OK
    (3) CHB0-7 HARDBREAK TEST   OK
    (4) CHC0-7 HARDBREAK TEST   OK
TEST20 ERAM HARD BREAK TEST2    (COUNT = 001)
    (1) SEQUENTIAL BREAK TEST   OK
    (2) RAR OVERFLOW BREAK TEST OK
    (3) CHC TIMEOUT BREAK TEST  OK
    (4) CHB0 INTERRUPT TEST     OK
TEST21 ERAM SOFT BREAK TEST      (COUNT = 001)      OK
TEST22 COMPULSORY BREAK TEST     (COUNT = 001)      OK
TEST23 ERAM TRACE TEST          (COUNT = 001)
    (1) SUBROUTINE TRACE TEST   OK
```



## Diagnostic Program Output Example (E8000 + EVCHIP Test) (cont)

```
(2) RANGE TRACE TEST          OK
(3) SUBROUTINE/RANGE TRACE TEST OK
(4) TRACE STOP TEST           OK
(5) TRACE SPECIAL CONDITION TEST OK
(6) TRACE SUPPRESS TEST       OK
(7) INRAM TRACE TEST          OK
(8) ERAM CONTINUOUS ACCESS TEST OK
(9) ERAM PC TRACE TEST        OK
TEST24 ERAM TIME MEASURE TEST (COUNT=001)
(1)SUBROUTINE TIME MEASURE TEST1 OK
(2)SUBROUTINE TIME MEASURE TEST2 OK
(3)SUBROUTINE TIME MEASURE TEST3 OK
(4)TIME STUMP TEST            OK
(5)A to B TIME MEASURE TEST    OK
TEST25 ERAM PARALLEL MONITOR TEST      (COUNT=001)    OK
TEST26 INROM WRITE PROTECT TEST (COUNT=001)    OK
TEST27 COVERAGE TEST      (COUNT=001)
(1) COVERAGE MEMORY R/W TEST    OK
(2) PC COVERAGE TEST            OK
TEST28 RESERVED   (COUNT=001)
TEST29 RESERVED   (COUNT=001)
TEST30 RESERVED   (COUNT=001)
TEST31 RESERVED   (COUNT=001)
TEST01 FLASH MEMORY READ TEST      (COUNT = 002)
(a)          (b)          (c)
(1) MONITOR SUM CHECK    OK
                        (d)
```

### Description:

- (a) Test item number
- (b) Test item
- (c) Execution count
- (d) Test result

## Section 5 Error Handling

If an error occurs, provide a Hitachi sales agency with a detailed description of the problem.

## Section 6 Testing Circuits and Connectors

### 6.1 Testing Circuit for P1284 I/F TEST (TEST07)

Connect the testing circuit that forms the loop in figure 6.1 to the bidirectional parallel interface connector on the E8000 emulator.

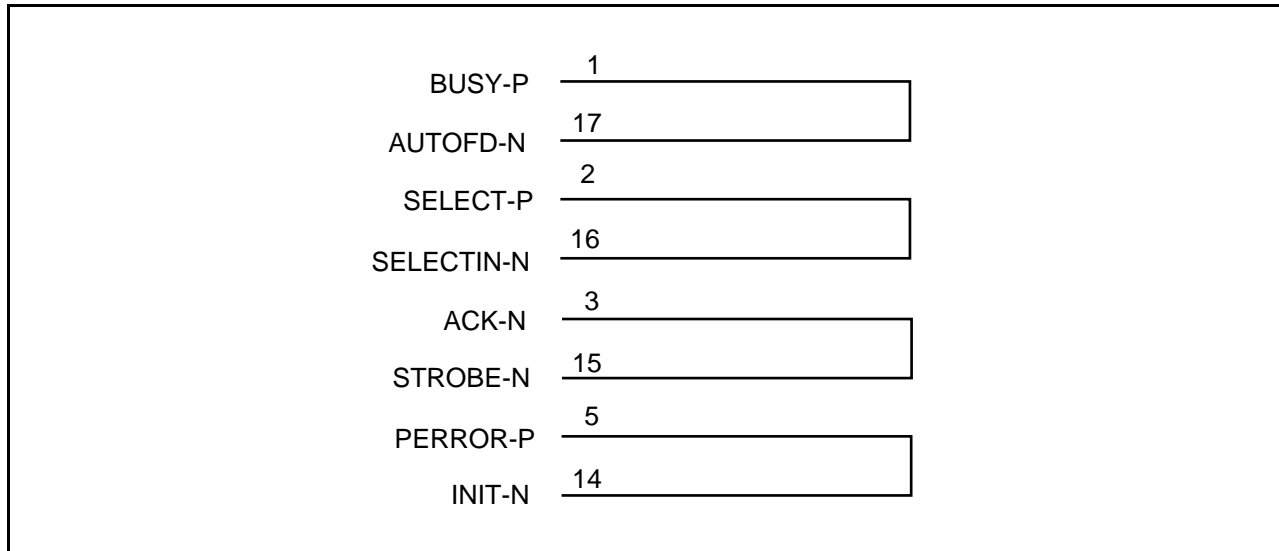


Figure 6.1 Testing Circuit for P1284 Loop Back Test

### 6.2 Testing Circuit for SERIAL I/F TEST (TEST08)

Connect the testing circuit in figure 6.2 to the serial interface connector on the E8000 emulator.

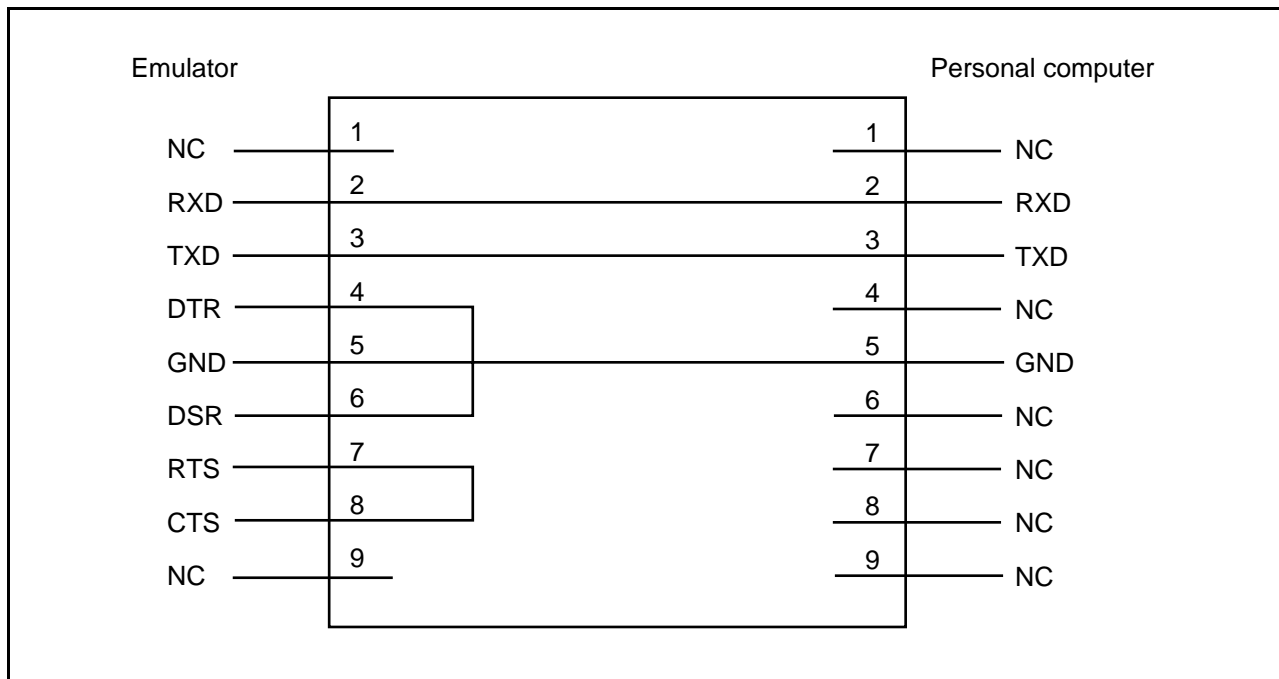
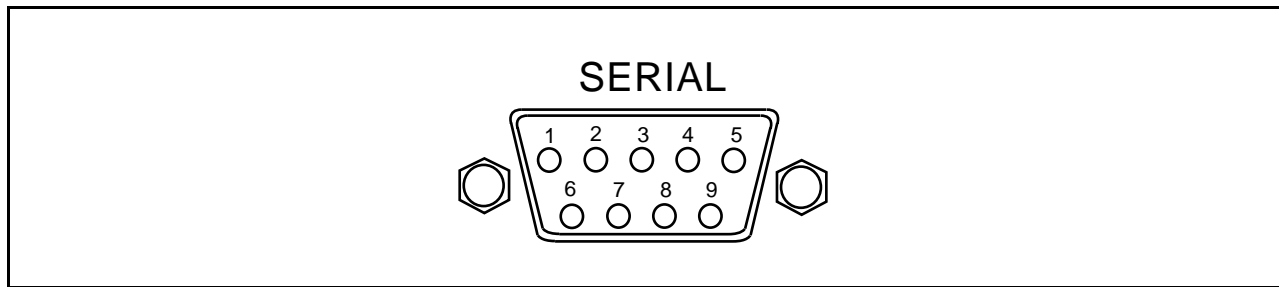


Figure 6.2 Testing Circuit for SERIAL I/F Test

### 6.3 Serial Interface Connector

Figure 6.3 shows pin locations in the serial interface connector on the E8000 emulator. Table 6.1 lists the signal name of each pin.



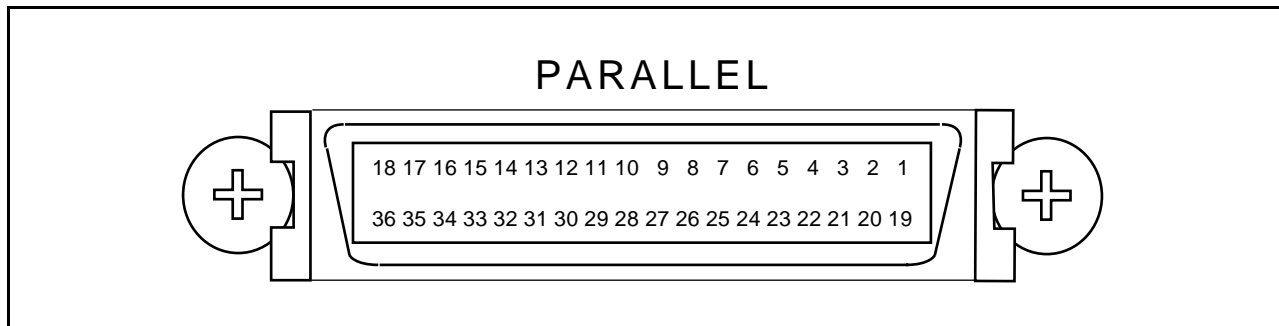
**Figure 6.3 Pin Locations in E8000 Emulator Serial Interface Connector**

**Table 6.1 Pin Signal Names in E8000 Emulator Serial Interface Connector**

Pin No.	Signal Name	Pin No.	Signal Name
1 and 9	NC	5	GND
2	RXD	6	DSR
3	TXD	7	RTS
4	DTR	8	CTS

## 6.4 Bidirectional Parallel Interface Connector

Figure 6.4 shows pin locations in the bidirectional parallel interface connector on the E8000 emulator. Table 6.2 lists the signal name of each pin.



**Figure 6.4 Pin Locations in E8000 Emulator Bidirectional Parallel Interface Connector**

**Table 6.2 Pin Signal Names in E8000 Emulator Bidirectional Parallel Interface Connector**

Pin No.	Signal Name	Pin No.	Signal Name
1	BUSY-P	11	SD5-P
2	SELECT-P	12	SD6-P
3	ACK-N	13	SD7-P
4	FAULT-N	14	INIT-N
5	PERROR-P	15	STROBE-N
6	SD0-P	16	SELECTIN-N
7	SD1-P	17	AUTOFD-N
8	SD2-P	18	HOSTLOGICHIGH
9	SD3-P	36	PERIPHERALLOGICHIGH
10	SD4-P	19 to 35	GND